

1. Record Nr.	UNINA9910783590503321
Autore	Sarid Dror
Titolo	Scanning force microscopy : with applications to electric, magnetic, and atomic forces / / Dror Sarid
Pubbl/distr/stampa	New York, New York ; ; Oxford, England : , : Oxford University Press, , 1994
ISBN	0-19-773261-5 1-280-44178-X 0-19-802281-6 9786610441785 0-19-534469-3 1-60256-628-3
Edizione	[Rev. ed.]
Descrizione fisica	1 online resource (xiii,263p.) : ill
Collana	Oxford series in optical and imaging sciences
Disciplina	502.82
Soggetti	Scanning force microscopy Surfaces (Physics)
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Previous ed.: 1991.
Nota di bibliografia	Includes bibliographical references (p. 233-259) and index.
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Sommario/riassunto

Includes information about the mapping of a variety of forces across surfaces, including basic theory, instrumentation, and applications. This book also includes research in SFM and a bibliography. It will be useful for academic and industrial researchers using SFM.
